

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/696,615 AHN ET AL.	
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U.S. PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,635,921	10-2003	Yi et al.	257/316
*	B	US-5,604,357	02-1997	Hori, Takashi	257/24
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
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